

## **OPTICAL TECHNIQUES WORKSHOP**

## Basic Contrast Methods Presented by:

Midwest Microscopy and Microanalysis Society
A local affiliate of the Microscopy Society of America
and the Microbeam Analysis Society

Wednesday, August 31, 2011
Hooke College of Applied Sciences,
a member of The McCrone Group
Westmont, IL
Map and directions:
http://www.hookecollege.com/area/

Space may be limited.

Please RSVP by Monday, August 22.

Email your contact information to:

Elaine Schumacher eschumacher@mccrone.com

(Tel: 630-887-7100)

Onsite Registration Fee: Free to MMMS members, \$20.00 for non-members, \$5.00 for students. (MMMS membership is included in the fee.) Lunch is included. We welcome vendor participation. Tables for literature and exhibits will be available. Please contact us for details.

8:00 am to 9:00 am Registration and coffee, Atrium and Café

**9:00 am to 9:15 am** Welcome and opening remarks, Auditorium

9:15 am to 10:15 am Basic Contrast Methods in Light Microscopy – Lecture and

Demonstration, John G. Delly, Hooke College of

Applied Sciences, Auditorium

Methods covered will include oblique illumination, darkfield illumination, Rheinberg illumination, phase contrast (Zernike and Heine methods), Nomarski differential interference contrast (DIC), and fluorescence.

The remainder of the morning and the afternoon sessions will consist of classroom demonstrations and hands-on exercises designed to illustrate the techniques described in the morning presentation. Activities will be led by John G. Delly and other McCrone Group staff members.

Lunch will be served in the Café from 11:45 am to 1:00 pm.

The program will end at approximately 4:30 pm. A tour of the McCrone Associates Laboratory will be offered afterward.